

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/575,861	MOTOZUKA ET	AL.
Examiner	Art Unit	
Tan V. Mai	2193	

SEARCHED					
Subclass	Date	Examiner			
230-236	7/22/2009	MAI			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	7/22/2009	MAI		